Sheet 1 of 1

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

KSB-003

ADDITION

APPLICANT

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Y. KAMOSHIDA .

FILING DATE

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GROUP 177

February 25, 2002

U.S. PATENT DOCUMENTS

U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NO. DATE NAME		NAME	CLASS	SUB- CLASS	FILING DATE	
	AA						<u> </u>	
	AB						40 0 0	
	AC						807. 807.	
	AD							
	ΑE						77	

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
M	АМ	Komatsu Ltd. Technical Document, Published October, 2000 (Japan)						
	AN							
	AO							

EXAMINER	Joseph Orodop	DATE CONSIDERED 1-30 -2003
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U.S. PATENT DOCUMENTS

02/25/02

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EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA	5 782 559	07/21/98	Neier et al.	Belo,	279	
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	AC	6 000 641	12/14/99	Komoriya et al.	241	29	
·	AD	<u> </u>					
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TR/ YES	NSLAT NO P	ION ART.
AG	4436659	04/95	DE				Х	
AH					<u> </u>		<u> </u>	
AI								
LA				<u> </u>				
 AK				<u> </u>				
AL		· 						

EXAMINER Greek Ordalas	DATE CONSIDERED 9 -30-203
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